MSKSEMI 美森科













ESD

SS

MOV

GDT

PIFD

AO3413

Product specification





Features

- -20V,-3A, RDS(ON) = $60m\Omega@VGS = -4.5V$
- Improved dv/dt capability
- Fast switching
- Green Device Available

Applications

- Notebook
- Load Switch
- Battery Protection
- Hand-held Instruments

BVDSS	RDSON	ID
-20V	60mΩ	-3A

Reference News

PACKAGE OUTLINE	PIN Configuration	Marking
SOT-23-3L	Go	AD**×

Absolute Maximum Ratings Tc=25℃ unless otherwise noted

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	-20	V
Vgs	Gate-Source Voltage	±12	V
	Drain Current - Continuous (Tc=25°C)	-3.0	Α
טו	Drain Current - Continuous (Tc=100°C)	-2.0	А
I _{DM}	Drain Current - Pulsed ¹	-12	Α
PD	Power Dissipation (Tc=25°C)	1.56	W
ГО	Power Dissipation - Derate above 25°C	0.012	W/°C
T _{STG}	Storage Temperature Range	-55 to 150	°C
TJ	Operating Junction Temperature Range	-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Тур.	Max.	Unit
Rеja	Thermal Resistance Junction to ambient		80	°C/W



Electrical Characteristics (TJ=25 ℃, unless otherwise noted)

Off Characteristics

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V , I _D =-250uA	-20			V
△BV _{DSS} /△T _J	BV _{DSS} Temperature Coefficient	Reference to 25°C , I _D =-1mA		-0.01		V/℃
Inco	Drain-Source Leakage Current	V _{DS} =-20V , V _{GS} =0V , T _J =25℃			-1	uA
IDSS	Drain-Oddice Leakage Guitern	V _{DS} =-16V , V _{GS} =0V , T _J =125℃			-10	uA
Igss	Gate-Source Leakage Current	V _{GS} = ±12V , V _{DS} =0V			±10	uA

On Characteristics

R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =-4.5V , I _D =-3A		60	80	mΩ
		V _{GS} =-2.5V , I _D =-2A		80	120	11152
V _{GS(th)}	Gate Threshold Voltage	-V _{GS} =V _{DS} , I _D =-250uA	-0.3	-0.65	-1.1	V
△V _{GS(th)}	V _{GS(th)} Temperature Coefficient	-VGS-VDS , ID2000/1		3		mV/°C
gfs	Forward Transconductance	V _{DS} =-10V , I _S =-1A		2.2		S

Dynamic and switching Characteristics

Dynamic a	id switching Characteristics			
Q_g	Total Gate Charge ^{2, 3}		 4.8	
Q _{gs}	Gate-Source Charge ^{2,3}	V _{DS} =-10V , V _{GS} =-4.5V , I _D =-3A	 0.5	 nC
Qgd	Gate-Drain Charge ^{2, 3}		 1.9	
T _{d(on)}	Turn-On Delay Time ^{2,3}		 3.5	
Tr	Rise Time ^{2, 3}	V _{DD} =-10V , V _{GS} =-4.5V ,	 12.6	 nS
T _{d(off)}	Turn-Off Delay Time ^{2, 3}	R _G =25Ω I _D =-1A	 32.6	 110
Tf	Fall Time ^{2, 3}		 8.4	
C _{iss}	Input Capacitance		 550	
Coss	Output Capacitance	V _{DS} =-10V , V _{GS} =0V , F=1MHz	 65	 pF
Crss	Reverse Transfer Capacitance		 55	

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current	V _G =V _D =0V,Force Current			-3.0	Α
Ism	Pulsed Source Current	- ,			-13	Α
Vsp	Diode Forward Voltage	V _{GS} =0V,I _S =-1A,T _J =25℃			-1.2	V

Note:

- Repetitive Rating : Pulsed width limited by maximum junction temperature. The data tested by pulsed , pulse width ≤ 300 us , duty cycle $\leq 2\%$.
- 2.
- Essentially independent of operating temperature.

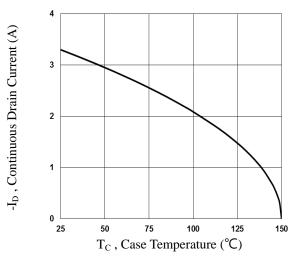


Fig.1 Continuous Drain Current vs. T_c

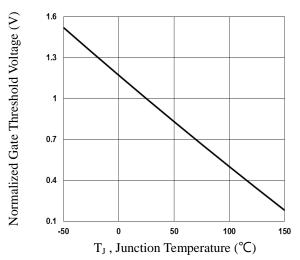


Fig.3 Normalized V_{th} vs. T_J

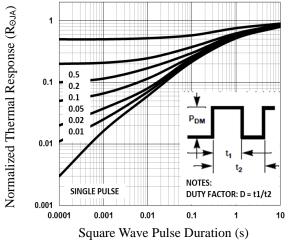


Fig.5 Normalized Transient Response

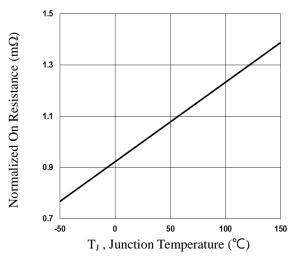


Fig.2 Normalized RDSON vs. T,

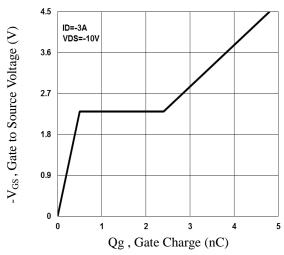


Fig.4 Gate Charge Waveform

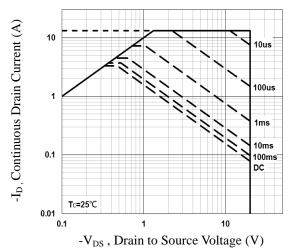
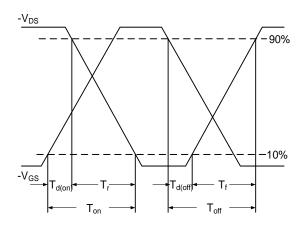
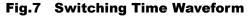


Fig.6 Maximum Safe Operation Area





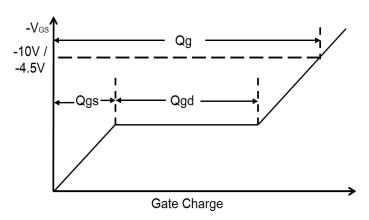
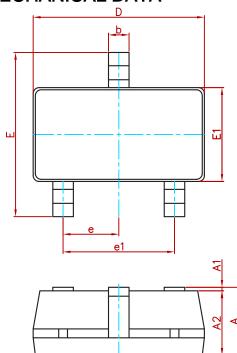
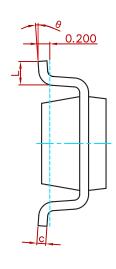


Fig.8 Gate Charge Waveform



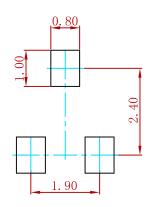
PACKAGE MECHANICAL DATA





Symbol	Dimensions II	n Millimeters	Dimension	s In Inches
Symbol	Min.	Max.	Min.	Max.
Α	1.050	1.250	0.041	0.049
A1	0.000	0.100	0.000	0.004
A2	1.050	1.150	0.041	0.045
b	0.300	0.500	0.012	0.020
С	0.100	0.200	0.004	0.008
D	2.820	3.020	0.111	0.119
E1	1.500	1.700	0.059	0.067
E	2.650	2.950	0.104	0.116
е	0.950(BSC)		0.037((BSC)
e1	1.800	2.000	0.071	0.079
L	0.300	0.600	0.012	0.024
θ	0°	8°	0°	8°

Suugested Pad Layout



Note:

- 1.Controlling dimension:in millimeters.
- 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

REELSPECIFICATION

P/N	PKG	QTY
AO3413	SOT-23-3L	3000



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